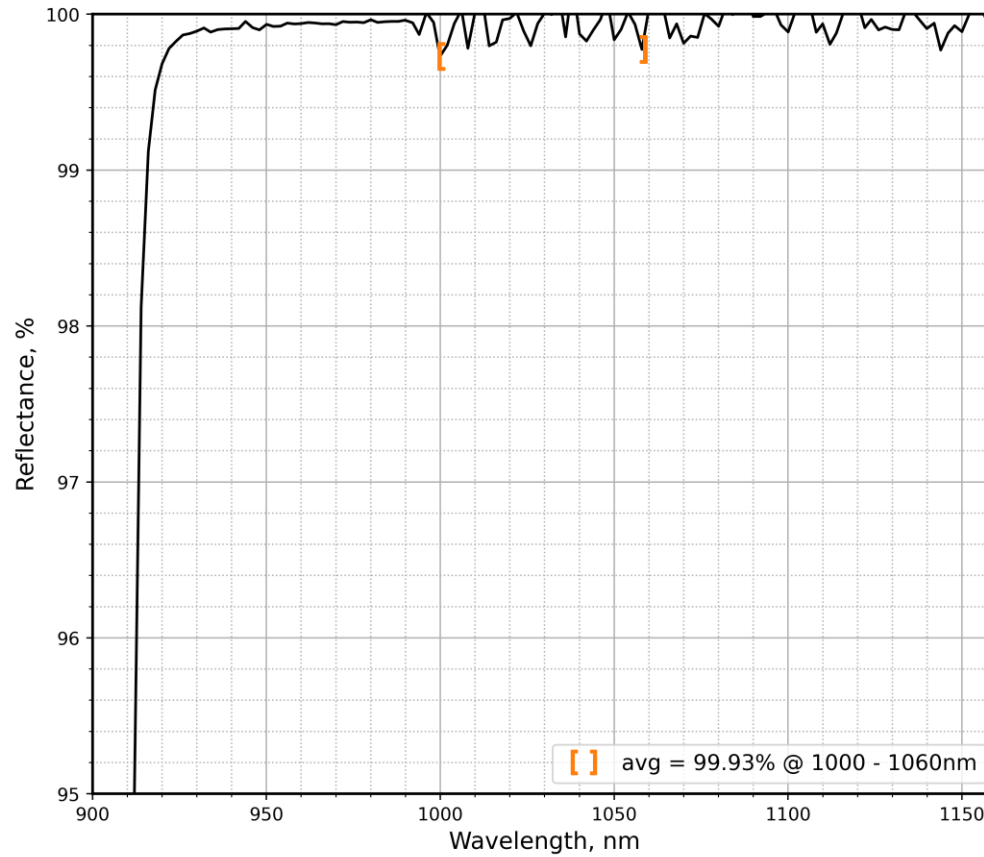


S1:(arrow mark) $R_s_{avg} > 99.95\%$ @ $R_p_{avg} > 99.9\%$ @ 1000-1060 nm, $|GDD_{Rs, Rp}| < 20 \text{ fs}^2$ @ 1000-1060 nm, AOI 45 deg
S2: uncoated



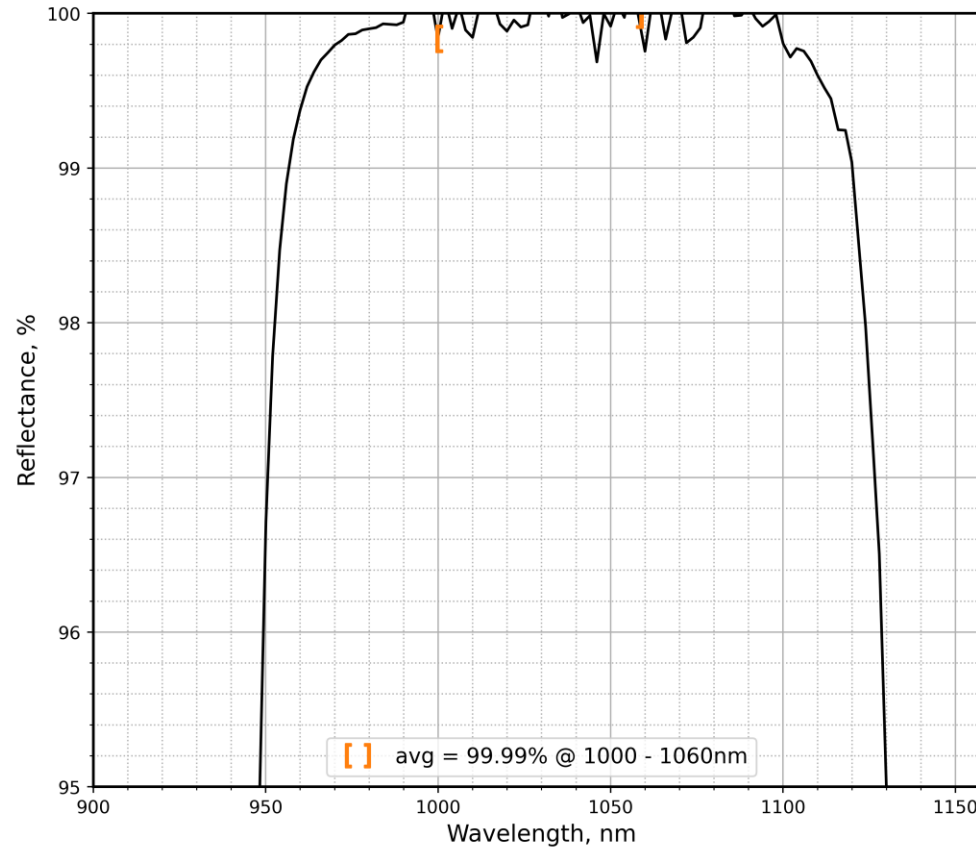
PO4993 Rs i45

Fig. 1.

SIDE MEASURED: S1 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%

S1:(arrow mark) R_s _avg>99.95% @ R_p _avg>99.9% @ 1000-1060 nm, |GDD R_s , R_p |<20 fs² @ 1000-1060 nm, AOI 45 deg
S2: uncoated



PO4993 Rp i45

Fig. 2.

SIDE MEASURED: S1 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%

Surface flatness, S1: $<\lambda/8@633\text{ nm}$ over CA

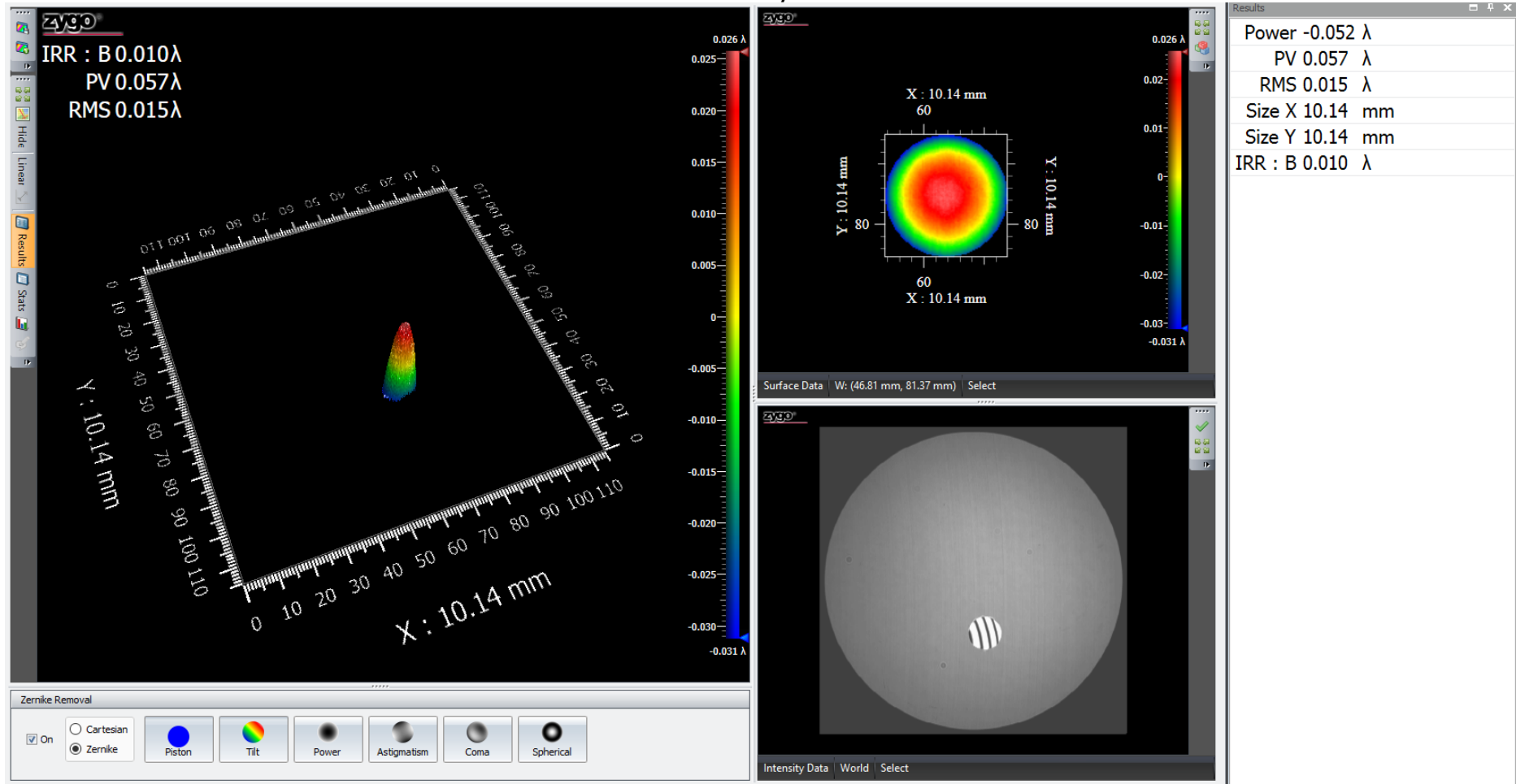


Fig. 3. Measured surface flatness 10.16 mm CA (sample 1)

SIDE MEASURED: S1

COMMENTS:

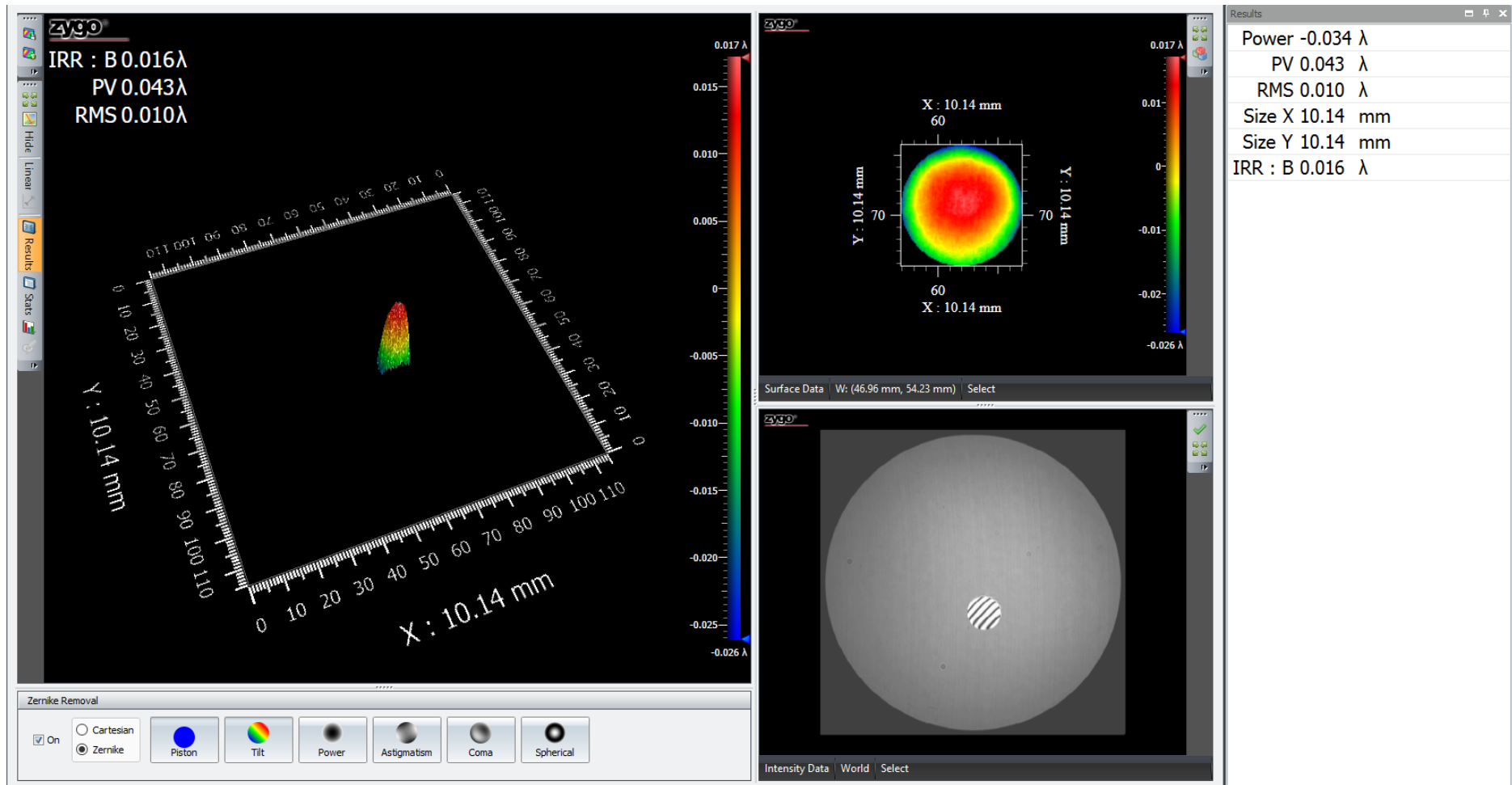


Fig. 4. Measured surface flatness 10.16 mm CA (sample 2)

SIDE MEASURED: S1

COMMENTS:

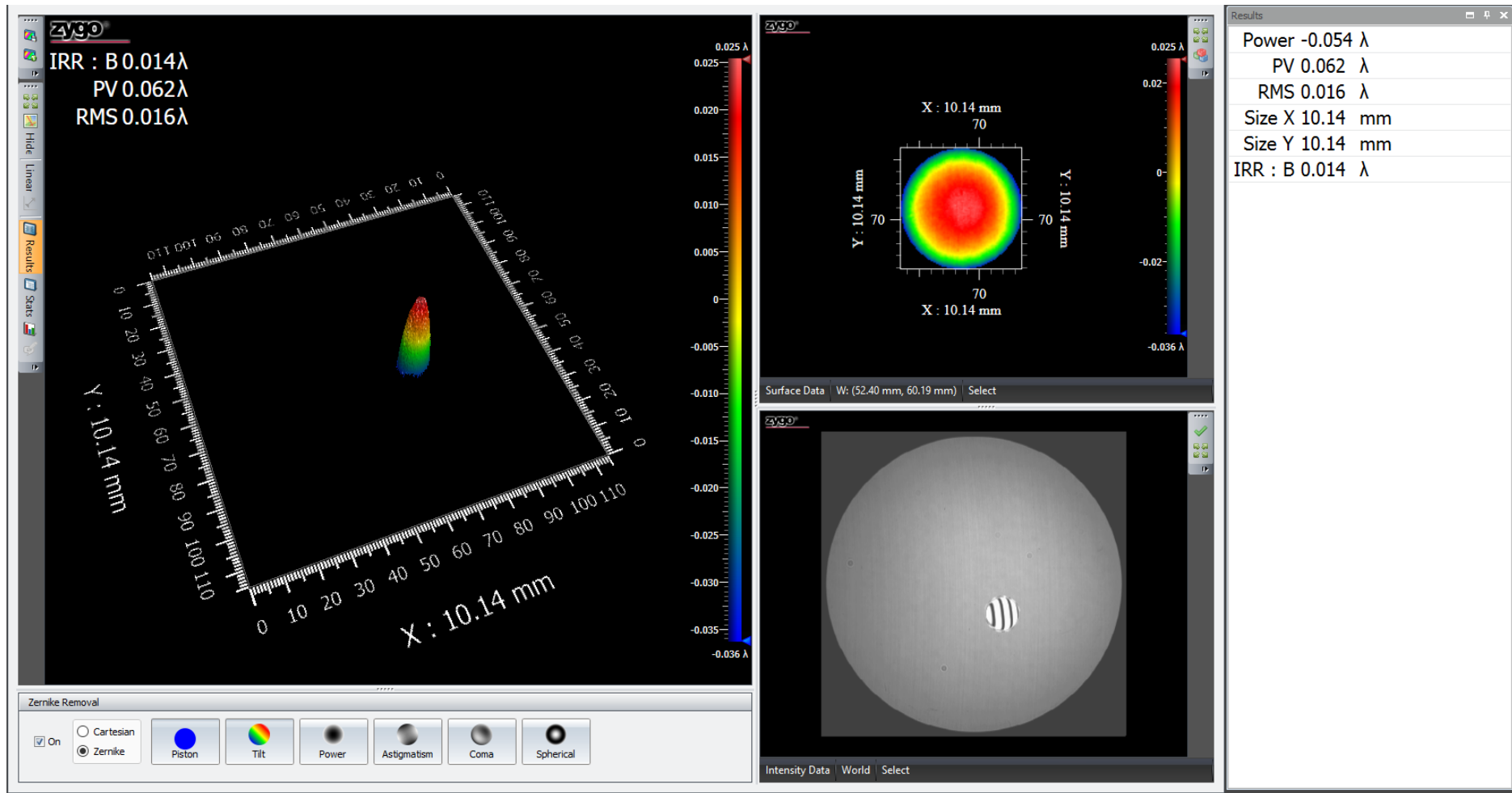


Fig. 5. Measured surface flatness 10.16 mm CA (sample 3)

SIDE MEASURED: S1

COMMENTS:

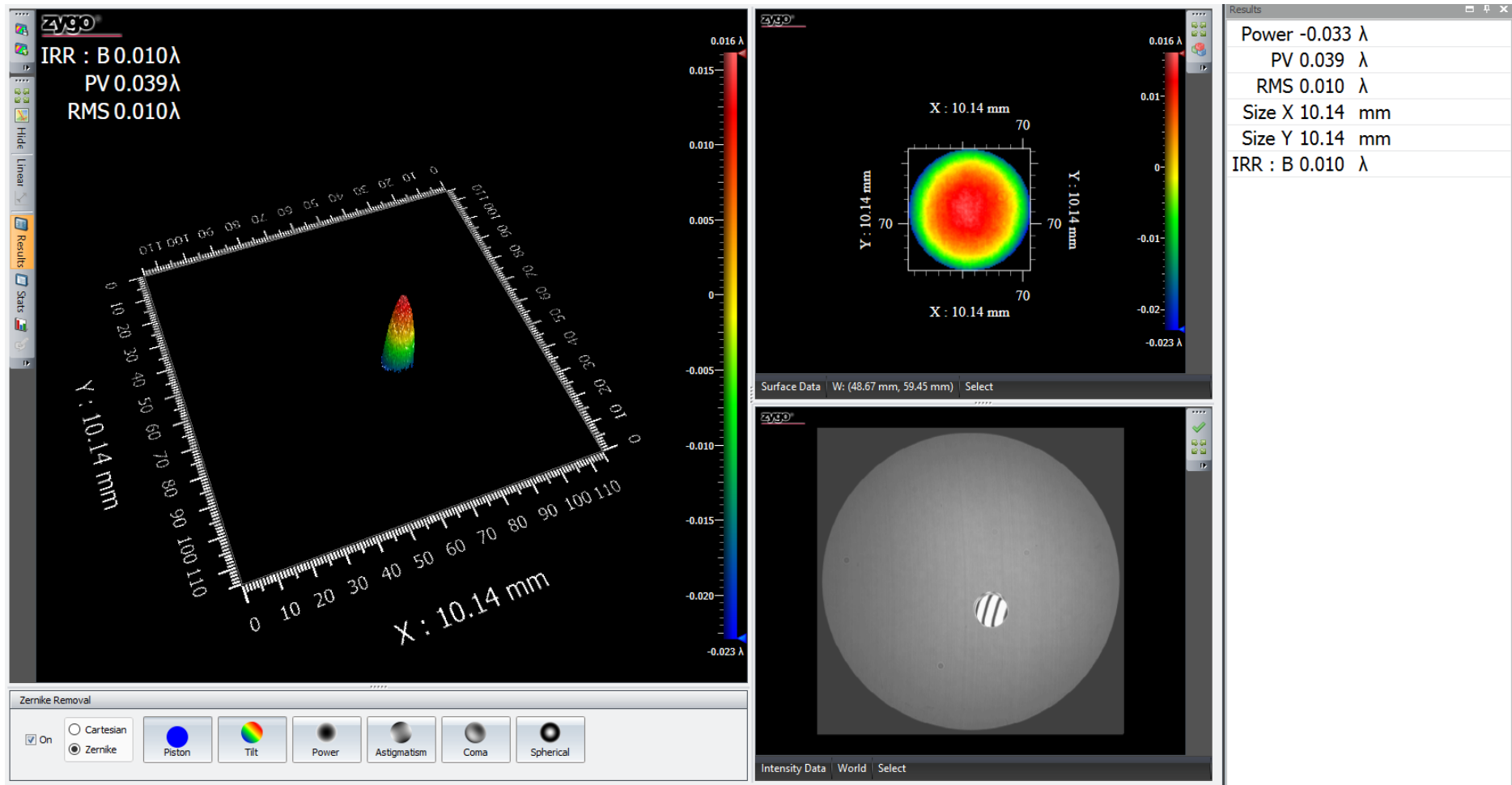


Fig. 6. Measured surface flatness 10.16 mm CA (sample 4)

SIDE MEASURED: S1

COMMENTS:

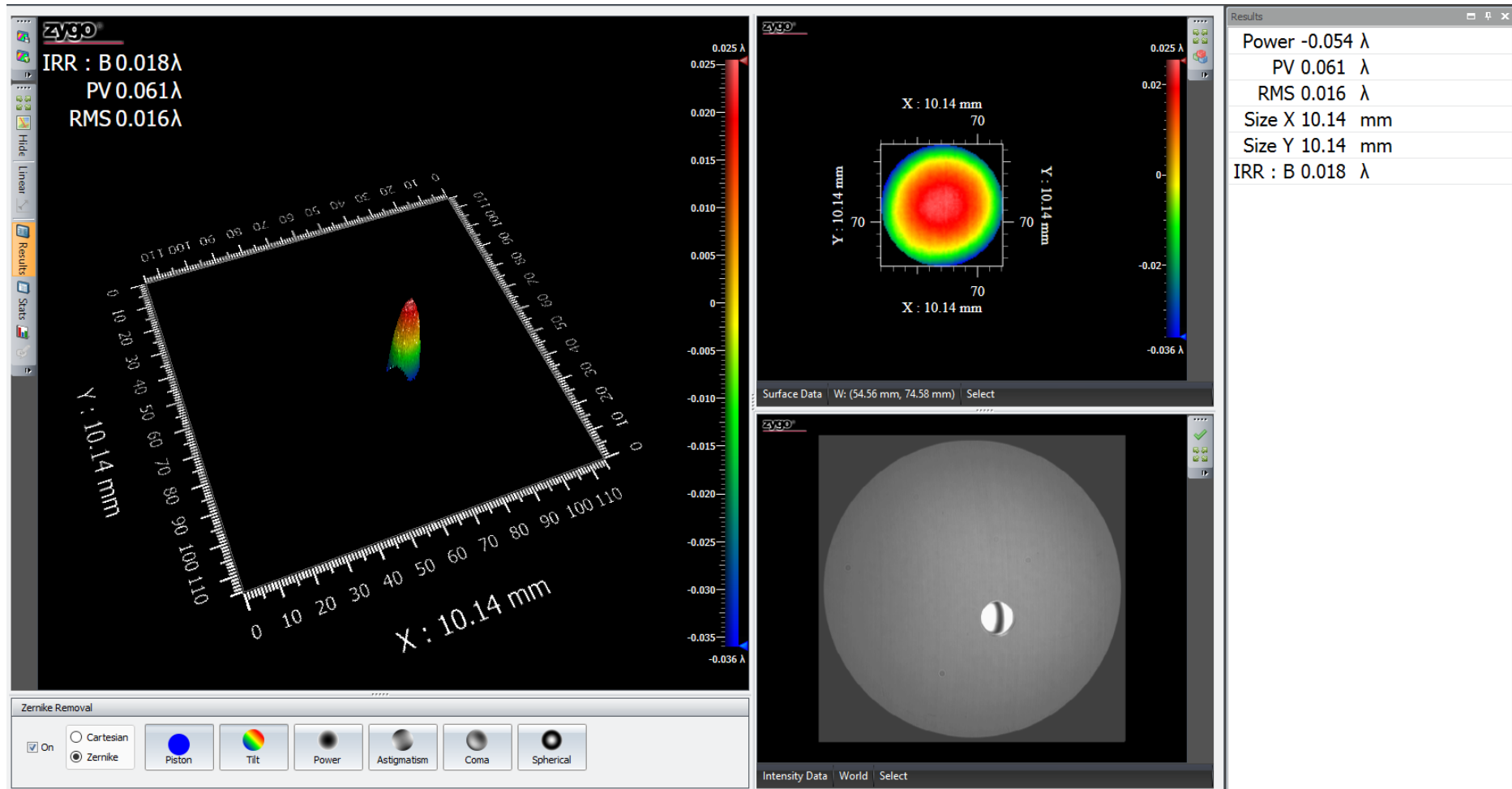


Fig. 7. Measured surface flatness 10.16 mm CA (sample 5)

SIDE MEASURED: S1

COMMENTS: